

Notice of References Cited	Application/Control No. 10/664,615	Applicant(s)/Patent Under Reexamination YAMAZAKI ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,455,357	09-2002	Kang et al.	438/158
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*	E	US-6,391,693	05-2002	Cho et al.	438/160
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